

Semiconductor

STOCK LIST

Mar.

2025year

< S Y S T E M >

No.	Maker	Item	Model	Vintage	Configuration	Remark
1	JEOL	FE-EPMA	JXA-8530F Plus	2017yr	•JXA-8530F Plus •EPMA Data processor •Phase analysis program •Irregular sample analysis program •Trace element analysis program •Phase map Maker •Liquid nitrogen trap •Chiller •Active Vibration removal stand	
2	JEOL	SEM	JSM-6510LV	2014yr	•JSM-6510LV •EDS AMETEK EDAX Octane Pro •Operation Keyboard •Motor Controlled Stage(2 Axis)	
3	JEOL	SEM	JSM-6360LV	2004yr	•JSM-6360LV SEM main unit •EDAX G-XM2 CDU/SUTW •61090(MS) 2-axis motor stage(Max specimen size 150 mm, 80x40mm) •47414 PC unit(2 USB port, PC card slot) •47512 CRT monitor •34470 backscatter electron detector •65020(PRD2) device for photography •65040(CSI2) device for scan Image photography •65150(OKB) operation keyboard •49020 chiller •LGSHL solvent holder	

4	Keyence	3D Surface Measurement Microscope	VE-9800S	2006yr	with 3D/Motorized Stage EDAX G-XM2 CDU/SUTW	
5	Olympus	Semiconductor wafer inspection microscope		2006yr	•Brightfield/Darkfield illuminator+Fiber Adapter(BX-RLA2+U-LGAD) •Motorized Nosepiece 6-Position RMS Threads(ob: 1.25x 2.5x 10x 20x 50x 100xBD)(U-D6REM) •Levo Controller/Hand switch(U-REMCB/U-HSTR) •Light Guide •Transmission Light unit •Imaging lens(Camera adapter)/touble port(U-TLU+U-TV0.5XC) •Light Reduction Filter/Color Temperature Conversion Filter •Color camera(Including the manual measurement function) •Stage and stage driving controller •Color video printers and ACC •Auto focus unit and PC	

Price is being negotiated (not secured/매입 검토중)

No.	Maker	Item	Model	Vintage	Configuration	Remark
1	Hitachi	SEM	S-3700N	2017yr	SEM, Large Sample Chamber (maximum 300mm diameter), 5-axis MD, Camera Navigation, Secondary/Reflection Electrons, Low Vacuum Secondary Electron Detector ESED-II, EDX HORIBA EMAX Evolution X Max50 EX470	
2	Hitachi	SEM	SU3500	2016yr	SEM, Secondary Electron Detector, Reflection Electron Detector, Low Vacuum Secondary Electron Detector, EDX (AMETEC Octane Plus), MC1000 ion Sputter, Etc.	
3	Hitachi	SEM	S-3400N	2011yr	SEM, Type1, Secondary Electron Detector, Reflection Electron Detector, Maximum Sample Size 200mm×35mm thickness, Turbo-Molecular Pump	
4	JEOL	SEM	JSM-IT500HR/LA	2020yr	SEM, SED (Dry SD 30 detector), Stage Navigation, Chamber Scope, Load Lock System, Large Table, Operation Panel	Upcoming in May.
5	JEOL	SEM	JSM-IT200LA	2019yr	SEM, EDS, Low Vacuum Secondary Electron Detector, Station Navigation, Chamber Scope, Carbon Coater, Freezing/Drying system	
6	Shimadzu	Microfocus X-Ray CT System	inspe X io SMX225CT FPD HR	2016yr	FPD-16, 8CL-H, Data processing system, Image analysis S/W, Sub work station, Etc.	
7	Leica	Stereo Microscope	M80	2017yr	M80, Objective lens Plan 1.0x, LED ring light, Binocular tilt lens barrel 45 degrees, Eyepiece 10x(x2), Ergo wedge, Photo tube, Digital camera MC170HD, C-mount, Flex Arm	

재고리스트 중 견적을 희망하는 장비가 있으시거나, 중고 분석/이화학 장비에 대한 추가적인 문의 사항이 있으신 분들께서는 아래의 이메일/전화를 통해 연락 부탁드립니다.

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